

ISO 25178 - Roughness (S-L)

S-filter (λ_s): Gaussian, 2.5 μm

F-operation: None

L-filter (λ_c): Gaussian, 0.8 mm

Height parameters

Sq 0.53 μm

Sa 0.43 μm

Spatial parameters

Sal 0.019 mm

Functional parameters (stratified surfaces)

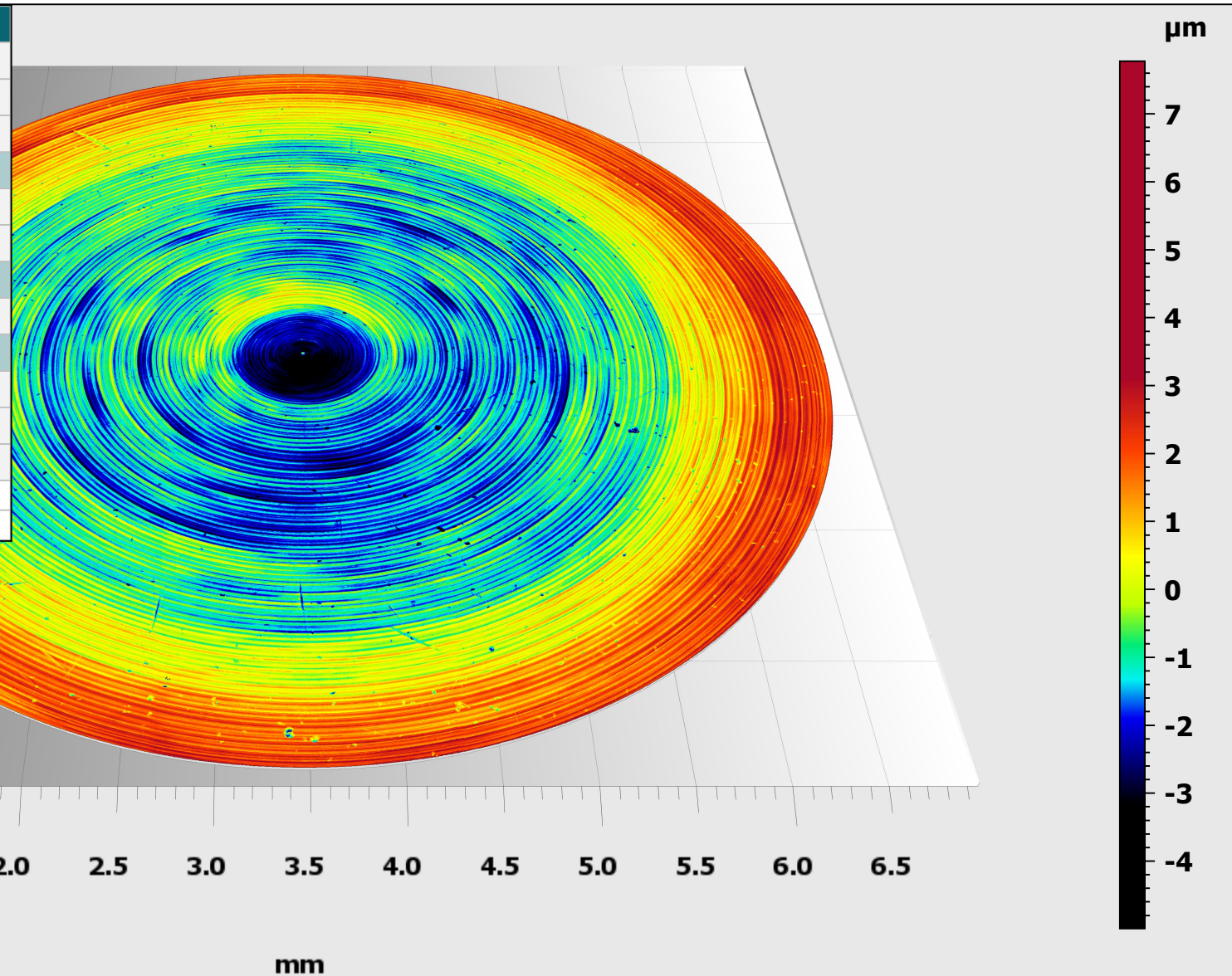
Sk 1.4 μm

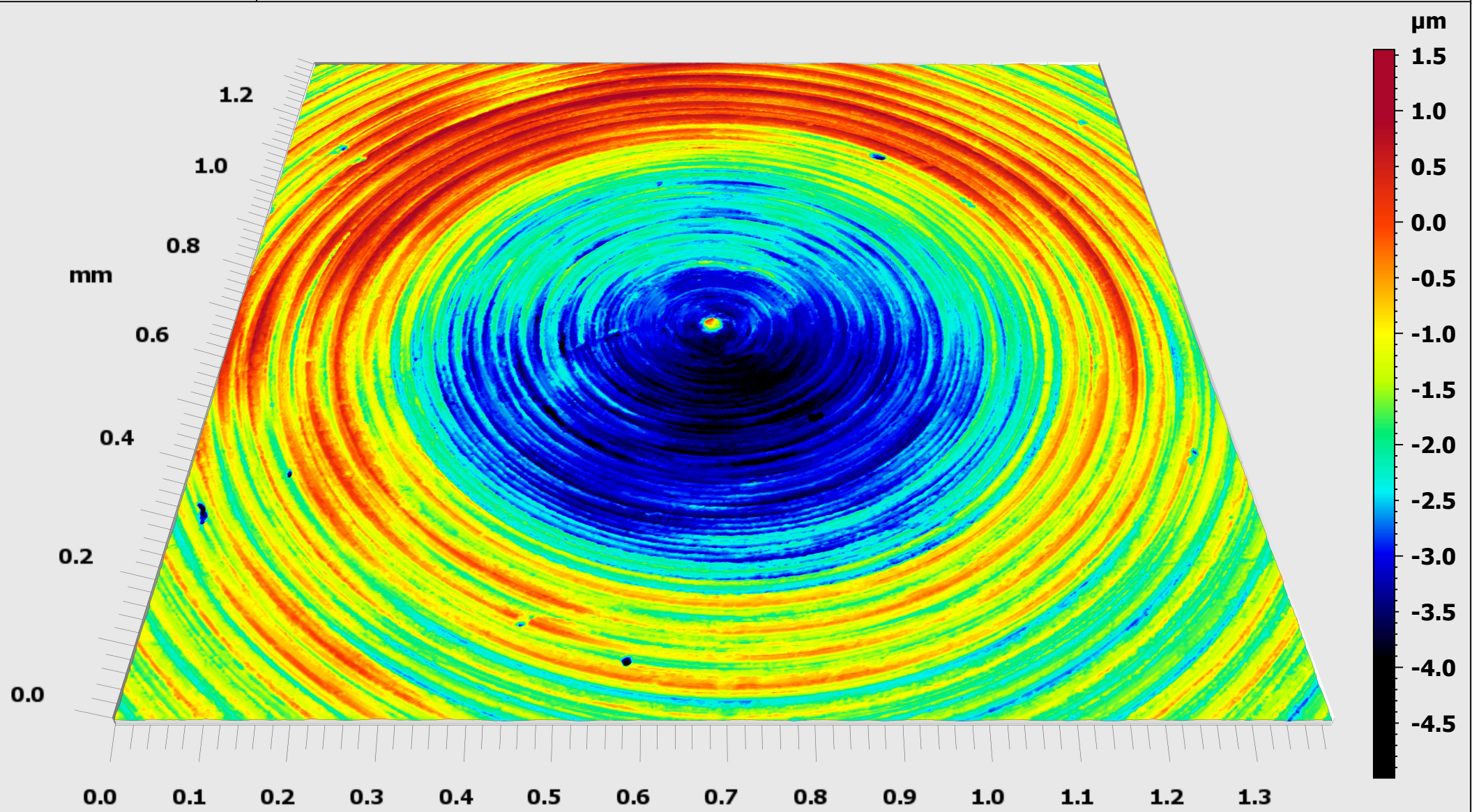
Spk 0.44 μm

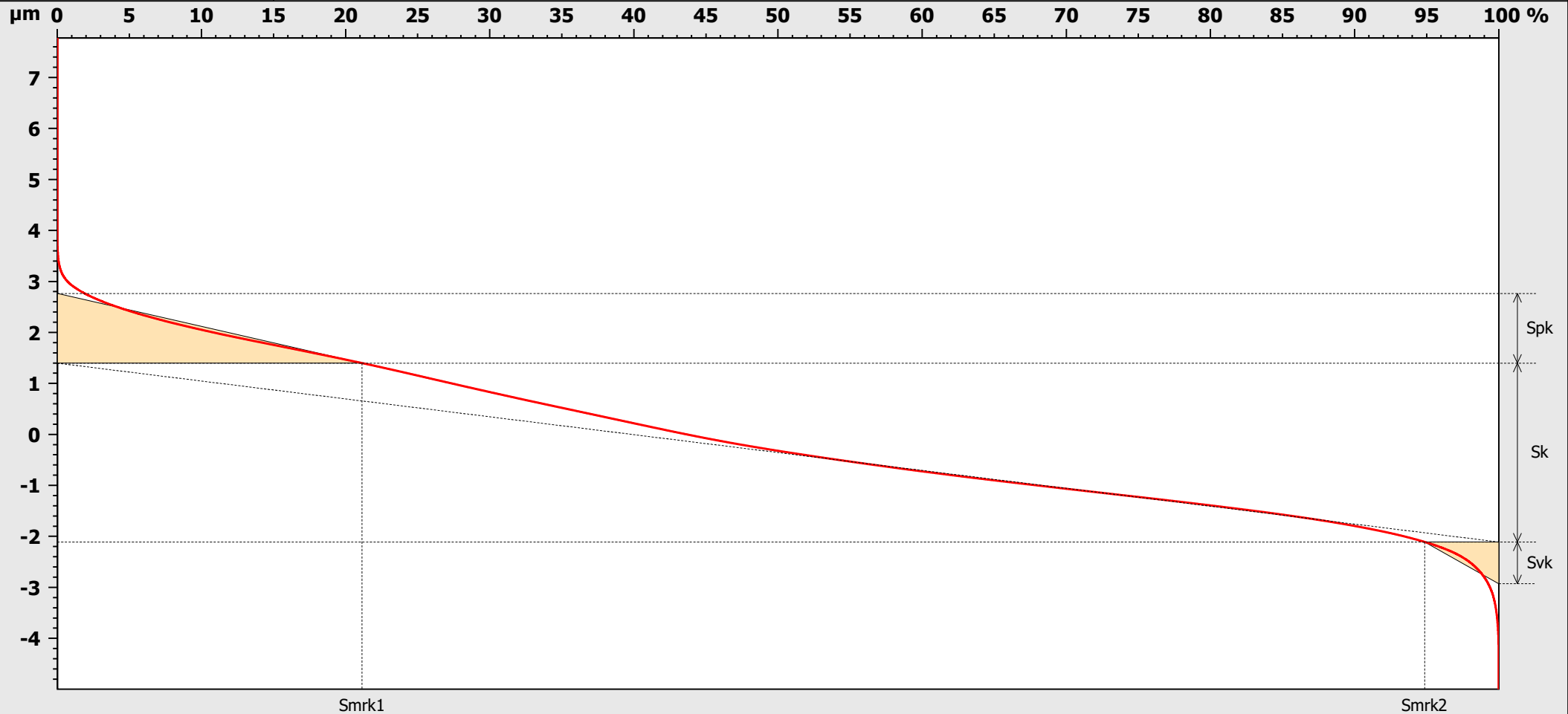
Svk 0.47 μm

Information

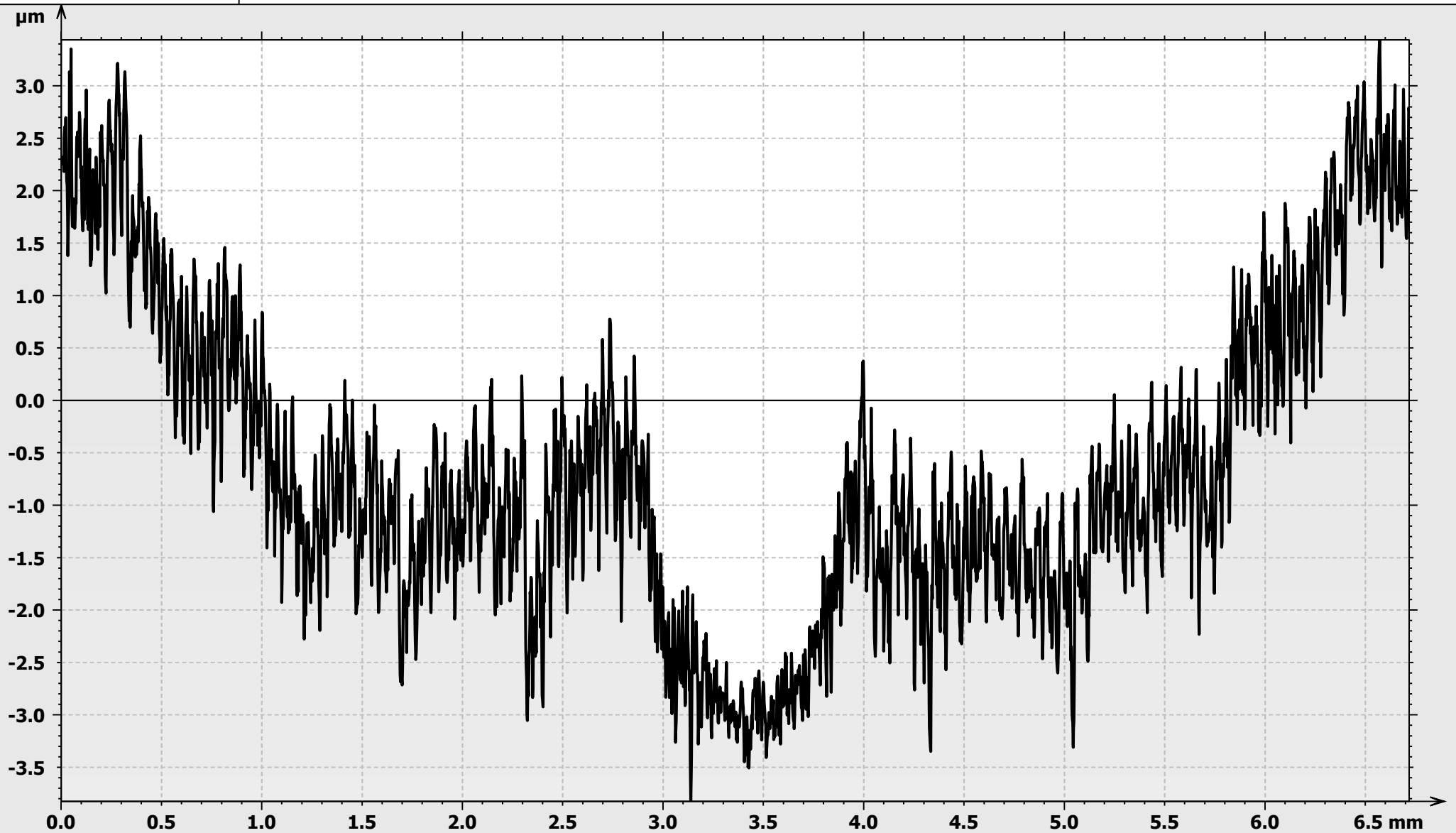
The studiabile contains non-measured points. The results are...

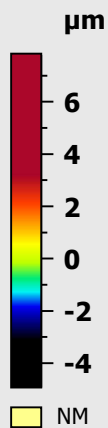
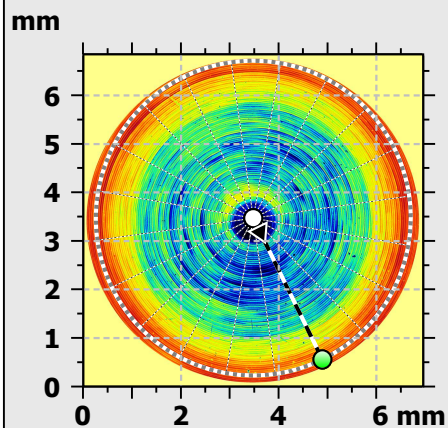
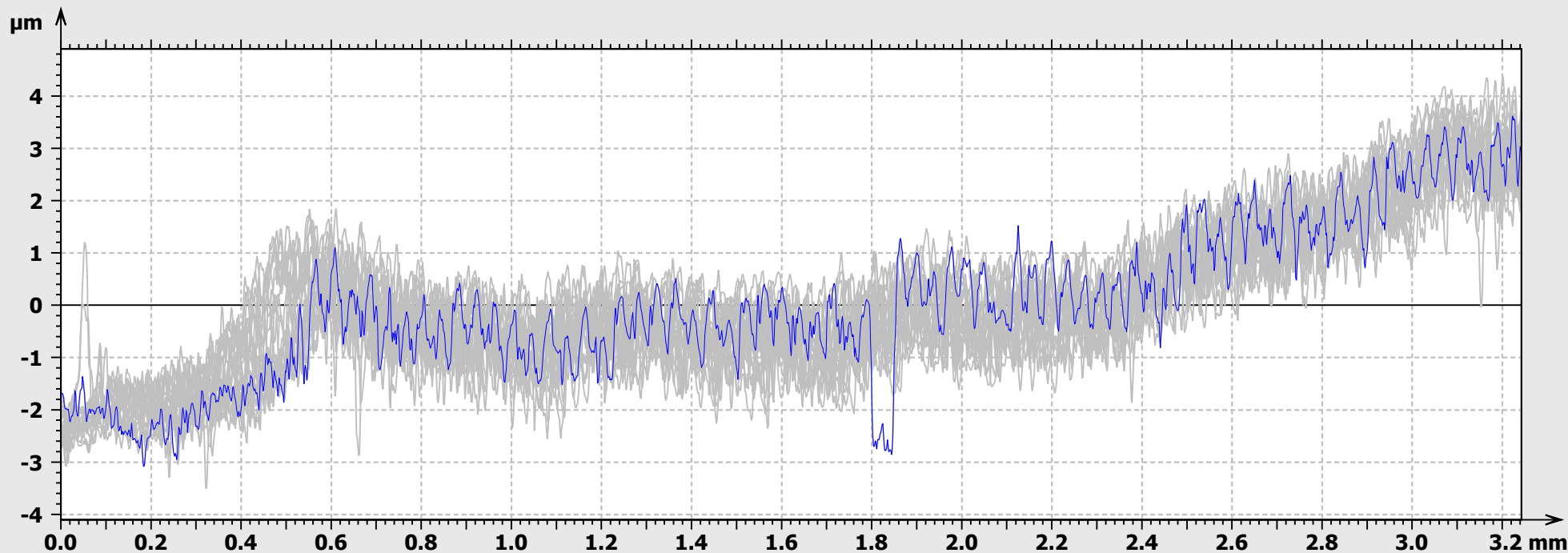






Parameters	Value	Unit
Sk	3.5	μm
Spk	1.4	μm
Svk	0.82	μm





	Context	Mean	Std dev	Min	Max
ISO 21920-Main - Roughness (S-L)					
<i>S-filter (λ_s): Gaussian, 2.5 μm</i>					
<i>F-operation: None</i>					
<i>L-filter (λ_c): Gaussian, 0.8 mm</i>					
<i>Evaluation length: All λ_c (4)</i>					
Height parameters					
Rq	μm	0.52	0.017	0.47	0.55
Rt	μm	3.4	0.56	2.7	5.4
Ra	μm	0.41	0.013	0.38	0.43